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|-----------------------------------|---------------------------------------|-------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 10/817,041 | Applicant(s)/Patent Under Reexamination CHETIA ET AL. | |
| | Examiner Huy D. Nguyen | Art Unit 2681 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|------------------------|----------------|
| * | A | US-2003/0220835 | 11-2003 | Barnes, Melvin L. JR. | 705/14 |
| * | B | US-6,836,667 | 12-2004 | Smith, Jr., Harold R. | 455/456.1 |
| * | C | US-6,711,408 | 03-2004 | Raith, Alex Krister | 455/440 |
| * | D | US-2004/0198386 | 10-2004 | Dupray, Dennis J. | 455/456.1 |
| * | E | US-6,829,475 | 12-2004 | Lee et al. | 455/419 |
| * | F | US-2003/0171991 | 09-2003 | Robbins, Michael Scott | 705/14 |
| * | G | US-2002/0161647 | 10-2002 | Gailey et al. | 705/14 |
| * | H | US-2003/0101451 | 05-2003 | Bentolila et al. | 725/34 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|----------------|----------------|
| | N | EP1379098A1 | 01-2004 | | Ross, Dliad N. | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

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